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Precision Measurements and Metrology Using Lasers

Guest Editor:

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Deadline for manuscript submissions:

closed (30 April 2014)

Message from the Guest Editor

Dear Colleagues,

Since its inception around 1960, the laser has found myriad applications in science, engineering, and medicine. The use of lasers in metrology includes the precise measurement of distance, velocity, acceleration, torque, strain, surface finish, and shape. For more than 50 years, the unique properties of laser radiation (i.e., coherence, narrow wavelength, low beam divergence and high intensity) have made lasers ideal for accurate and repeatable non-contact measurement. This special issue aims to publish new research and novel applications in all types of laser metrology and precision measurement. It is my pleasure to encourage both theoretical and empirical papers in this ever-expanding and exciting discipline.

Dr. David Kerr











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Editor-in-Chief

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Message from the Editor-in-Chief

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